

Change in the parameters of electron-irradiated 4H-SiC Schottky diodes as a function of the time during low-temperature isothermal annealing

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Comparative results of low temperature annealing of lightly doped n-layers of silicon carbide irradiated by protons and electrons

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Dependence of the carrier removal rate in 4H-SiC PN structures on irradiation temperature

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DLTS measurements on 4H-SiC JBS-diodes with boron implanted local p-n junctions

Ivanov, Pavel; **Korolkov, Oleg**; Samsonova, Tatyana; **Sleptsuk, Natalja**; Potapov, Alexander; **Toompuu, Jana**; **Rang, Toomas** Materials science forum 2011 / p. 409-412 https://www.researchgate.net/publication/272046403_DLTS_measurements_on_4H-SiC_JBS-diodes_with_boron_implanted_local_p-n_junctions